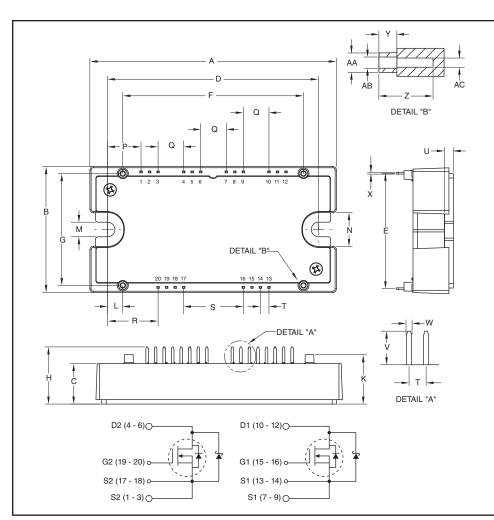


# QJD1210011 Preliminary

## Split Dual SiC MOSFET Module 100 Amperes/1200 Volts

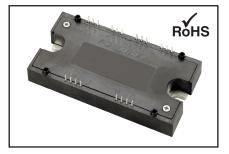


### **Outline Drawing and Circuit Diagram**

Dimensions	Inches	Millimeters
А	4.32	109.8
В	2.21	56.1
С	0.71	18.0
D	3.70±0.02	94.0±0.5
E	2.026	51.46
F	3.17	80.5
G	1.96	49.8
Н	1.00	25.5
К	0.87	22.0
L	0.266	6.75
М	0.26	6.5
Ν	0.59	15.0
Р	0.586	14.89

Dimensions	Inches	Millimeters
Q	0.449	11.40
R	0.885	22.49
S	1.047	26.6
Т	0.15	3.80
U	0.16	4.0
V	0.30	7.5
W	0.045	1.15
Х	0.03	0.8
Y	0.16	4.0
Z	0.47	12.1
AA	0.17 Dia.	4.3 Dia.
AB	0.10 Dia.	2.5 Dia.
AC	0.08 Dia.	2.1 Dia.

Information presented is based upon manufacturers testing and projected capabilities. This information is subject to change without notice. The manufacturer makes no claim as to the suitability of use, reliability, capability, or future availability of this product. 12/30/14 Rev. 5



### **Description:**

Powerex Silicon Carbide MOSFET Modules are designed for use in high frequency applications. Each module consists of two MOSFET Silicon Carbide Transistors with each transistor having a reverse connected fast recovery free-wheel silicon carbide Schottky diode. All components and interconnects are isolated from the heat sinking baseplate, offering simplified system assembly and thermal management.

### Features:

- □ Junction Temperature: 175°C
- □ Silicon Carbide Chips
- □ Low Internal Inductance
- □ Industry Leading RDS(on)
- □ High Speed Switching
- Low Switching Losses
- □ Low Capacitance
- □ Low Drive Requirement □ Fast 100A Free Wheeling
- Schottky Diode
- □ High Power Density
- □ Isolated Baseplate
- □ Aluminum Nitride Isolation
- □ 2 Individual Switches
  - per Module
- □ AlSiC Baseplate□ RoHS Compliant

## Applications:

- Energy Saving Power Systems such as: Fans; Pumps; Consumer Appliances
- High Frequency Type Power Systems such as: UPS; High Speed Motor Drives; Induction Heating; Welder; Robotics
- High Temperature Power
  Systems such as:
  Power Electronics in Electric
  Vehicle and Aviation Systems



#### QJD1210011

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### Absolute Maximum Ratings, $T_j = 25$ °C unless otherwise specified

Ratings	Symbol	QJD1210011	1 Units	
Drain-Source Voltage (G-S Short)	VDSS	1200	Volts	
Gate-Source Voltage	VGSS	-5 / +25	Volts	
Drain Current (Continuous) at T <sub>C</sub> = 150°C	۱D	100	Amperes	
Drain Current (Pulsed)*	ID(pulse)	250	Amperes	
Maximum Power Dissipation (T <sub>C</sub> = 25°C, T <sub>j</sub> < 175°C)	PD	900	Watts	
Junction Temperature	Тј	-40 to 175	°C	
Storage Temperature	T <sub>stg</sub>	-40 to 150	°C	
Mounting Torque, M6 Mounting Screws	_	40	in-lb	
Module Weight (Typical)	_	140	Grams	
V Isolation Voltage	V <sub>RMS</sub>	3000	Volts	

\* Pulse width and repetition rate should be such that device junction temperature  $(T_j)$  does not exceed  $T_{j(max)}$  rating.



#### QJD1210011

**Split Dual SiC MOSFET Module** 100 Amperes/1200 Volts

### MOSFET Characteristics, $T_j = 25$ °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Тур.	Max.	Units
Drain-Source Breakdown Voltage	V(BR)DSS	$I_{D} = 50 \mu A, V_{GS} = 0$	1200	_	_	Volts
Zero Gate Voltage Drain Current**	IDSS	$V_{GS} = 0, V_{DS} = 1200V$	_	0.35	2.6	mA
Zero Gate Voltage Drain Current**	IDSS	$V_{GS} = 0, V_{DS} = 1200V, T_j = 175^{\circ}C$	_	0.40	4.0	mA
Gate Leakage Current	IGSS	$V_{DS} = 0, V_{GS} = 20V$	_	_	1.5	μA
Gate Threshold Voltage	VGS(th)	$V_{DS} = V_{GS}, I_D = 10 \text{mA}$	1.5	2.5	5.0	Volts
		$V_{DS} = V_{GS}, I_{D} = 10mA, T_{j} = 175^{\circ}C$	1.0	1.7	5.0	Volts
Drain-Source On Resistance	R <sub>DS(on)</sub>	$I_{D} = 100A, V_{GS} = 20V$	_	15	25	mΩ
		$I_D = 100A, V_{GS} = 20V, T_j = 175^{\circ}C$	_	20	32	mΩ
Gate to Source Charge	Q <sub>gs</sub>	V <sub>DD</sub> = 800V, I <sub>D</sub> = 100A	_	140	_	nC
Gate to Drain Charge	Q <sub>gd</sub>	V <sub>DD</sub> = 800V, I <sub>D</sub> = 100A	_	220	_	nC
Total Gate Charge	QG	$V_{CC} = 800V, I_{C} = 100A, V_{GS} = -5/20V$	_	500	_	nC
Body Diode Forward Voltage	V <sub>SD</sub>	IF = 50A, V <sub>GS</sub> = -5V	_	4.0	_	Volts
Input Capacitance	C <sub>iss</sub>		_	10.2	_	nF
Output Capacitance	C <sub>oss</sub>	V <sub>GS</sub> = 0, V <sub>DS</sub> = 800V, f = 1MHz	_	1.0	_	nF
Reverse Transfer Capacitance	C <sub>rss</sub>		_	0.1	_	nF
Turn-on Delay Time	<sup>t</sup> d(on)	V <sub>DD</sub> = 800V, I <sub>D</sub> = 100A,	_	17.2	_	ns
Rise Time	tr	V <sub>GS</sub> = -2/20V,	_	13.6	_	ns
Turn-off Delay Time	<sup>t</sup> d(off)		_	62	_	ns
Fall Time	tf	Inductive Load	_	35.6	_	ns

\*\*Total module leakage includes MOSFET leakage plus reverse Schottky diode leakage.



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### Reverse Schottky Diode Characteristics, $T_j = 25$ °C unless otherwise specified

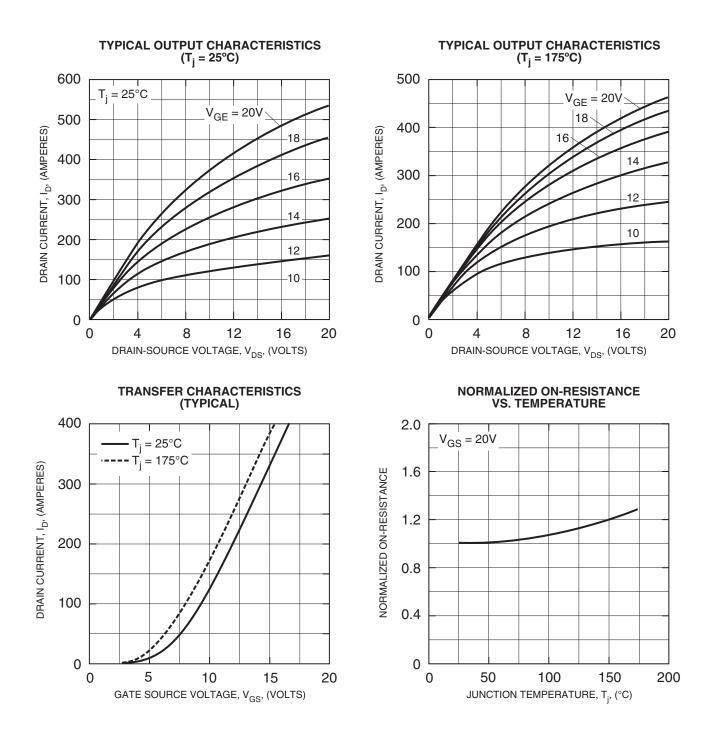
Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Diode Forward Voltage	VFM	$I_{F} = 100A, V_{GS} = -5V$	—	1.6	2.0	Volts
		$I_F = 100A$ , $V_{GS} = -5V$ , $T_j = 175^{\circ}C$	—	2.5	3.2	Volts
Diode Capacitive Charge	QC	$V_R$ = 1200V, I <sub>F</sub> = 100A, di/dt = 4000A/µs	—	550	—	nC

## Thermal and Mechanical Characteristics, $T_j = 25$ °C unless otherwise specified

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Thermal Resistance, Junction-to-Case	R <sub>th(j-c)</sub>	MOSFET Part	—	—	0.167	°C/W
Thermal Resistance, Junction-to-Case	R <sub>th(j-c)</sub>	Diode Part	—	—	0.294	°C/W
Contact Thermal Resistance	R <sub>th(c-s)</sub>	Per 1/2 Module, Thermal Grease Applied	—	0.04	—	°C/W
Internal Inductance	L <sub>int</sub>	MOSFET Part	—	10	—	nH

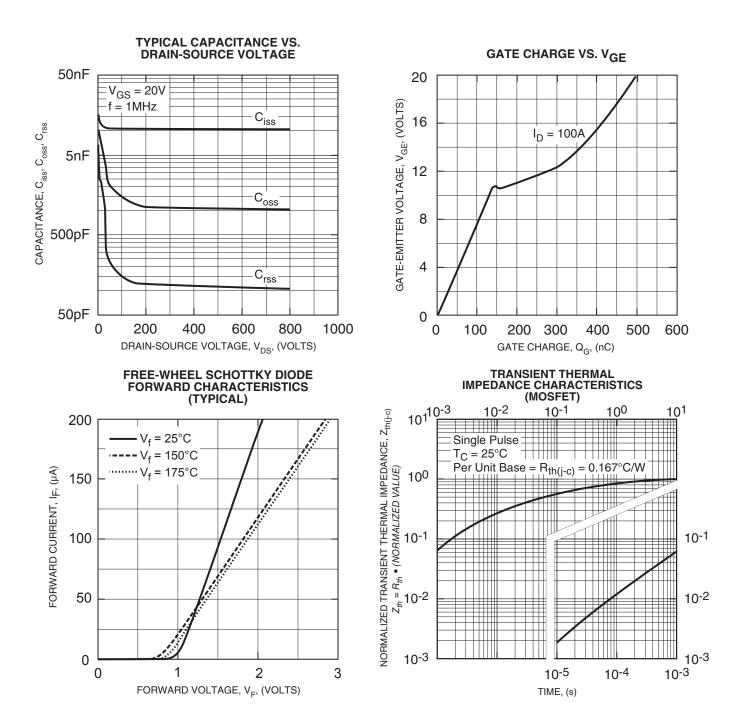


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